## ELECTROMAGNETO-OPTICAL EFFECT IN FERRIMAGNETIC/PIEZOELECTRIC STRUCTURE

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The electro-magneto-optical effect (EMOE) as a magnetoelectric response for ferrimagnetic/piezoelectric (yttrium iron garnets (YIG)/lead zirconate titanate (PZT)) structure by applying an external electrical field was registered using optical polarimetry method. The heart of the method is the registration of the electric-field-induced changes the magneto-optical Faraday rotation of the investigated structure –  $\alpha_{EMO}$  [1]. Our experimental setup consists of a high-sensitive laser polarimeter, described in [2]. The sample represented the hybrid structure with stuck together thin magnetostriction (YIG film) and a piezoelectric (PZT) plates. The sample was placed between the optically transparent electrodes which were used to apply an external electric field. The He-Ne laser ( $\lambda$  =0.63  $\mu$ m) was used in the experiment. EMOE characterization ( $\alpha_{EMO}$ ) was carried out as a function of the static electric field  $E_-$ 

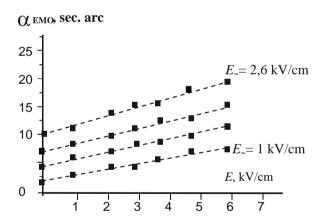


Fig. 1. Dependencies of  $\alpha_{EMO}$  from static electric field measured in variable electric field  $E_{\sim}$  ( $E_{\sim}=1$  kV/cm,  $E_{\sim}=1,5$  kV/cm,  $E_{\sim}=2$  kV/cm,  $E_{\sim}=2.6$  kV/cm).

when magnetic field H = 0. Sample was subjected to a static electric field  $E_{-}$  perpendicular to its plane and the electric field dependences (Fig. 1) were obtained for a series of variable electric fields  $E_{\sim}$ . A linear dependence of the field shift upon the electric field is evident from Fig. 1. We shown that YIG/PZT structure possess effective EMOE which is a result of magnetoelectric effect in magnetic phase (YIG film) and magnetostriction/piezoeffect. The EMOE for investigated structure is approximately in one order higher than for separate ferrimagnetic phase (YIG film) [3].

## References

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